



# FDS6690A

# Single N-Channel, Logic-Level, PowerTrench® MOSFET

## **General Description**

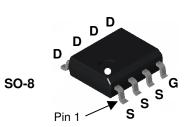
This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

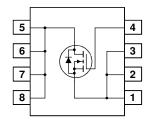
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.



## **Features**

- 11 A, 30 V.  $R_{DS(ON)} \, = 12.5 \; m\Omega \; @ \; V_{GS} = 10 \; V$   $R_{DS(ON)} \, = 17.0 \; m\Omega \; @ \; V_{GS} = 4.5 \; V$
- · Fast switching speed
- · Low gate charge
- High performance trench technology for extremely low Rps/ONL
- High power and current handling capability





## Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	11	Α
	- Pulsed		50	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.0	
E <sub>AS</sub>	Single Pulse Avalanche Energy	(Note 3)	96	mJ
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

## **Thermal Characteristics**

R <sub>eJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1b)	125	
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	25	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6690A	FDS6690A	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		1	1		1
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 250  \mu\text{A}$	30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		25		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	μΑ
		$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55^{\circ}\text{C}$			10	μΑ
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V},  V_{DS} = 0 \text{ V}$			±100	nA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1	1.9	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		<b>-</b> 5		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$\begin{split} V_{GS} &= 10 \ V, & I_D = 11 \ A \\ V_{GS} &= 4.5 \ V, & I_D = 10 \ A \\ V_{GS} &= 10 \ V, I_D = 11 \ A, T_J = 125 ^{\circ}C \end{split}$		9.8 12.0 13.7	12.5 17.0 22.0	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	50			Α
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 11 \text{ A}$		48		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1205		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		290		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	7		115		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		2.4		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$		9	19	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		5	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			28	44	ns
t <sub>f</sub>	Turn-Off Fall Time			9	19	ns
$Q_g$	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 11 \text{ A},$		12	16	nC
$Q_{gs}$	Gate-Source Charge	$V_{GS} = 5 V$		3.4		nC
$Q_{gd}$	Gate-Drain Charge			4.0		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	e Diode Forward Current			2.1	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{S} = 2.1 \text{ A (Note 2)}$		0.74	1.2	٧
t <sub>rr</sub>	Diode Reverse Recovery Time	L 11 A d /d 100 A/us		24		nS
Qrr	Diode Reverse Recovery Charge	$I_F = 11 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		27		nC

## Notes:

R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



a) 50 °C/W when mounted on a 1in² pad of 2 oz copper



b) 125°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2 Test: Pulse Width < 300μs, Duty Cycle < 2.0%
3. Starting TJ = 25°C, L = 3mH, I<sub>AS</sub> = 8A, V<sub>DD</sub> = 30V, V<sub>GS</sub> = 10V

## **Typical Characteristics**

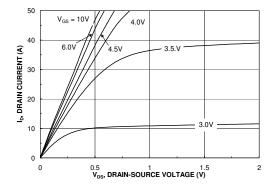


Figure 1. On-Region Characteristics.

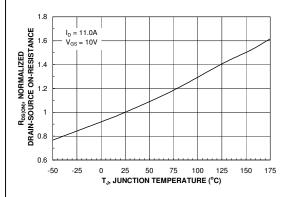


Figure 3. On-Resistance Variation with Temperature.

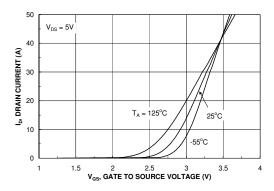


Figure 5. Transfer Characteristics.

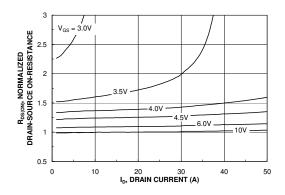


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

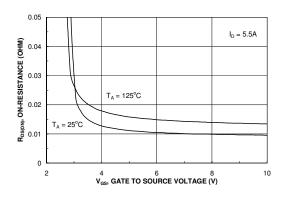


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

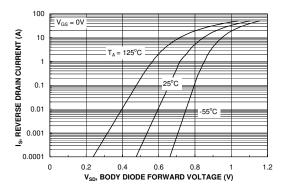
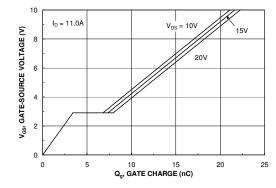


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



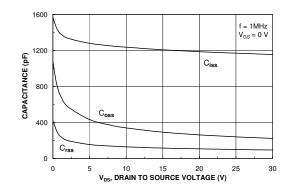
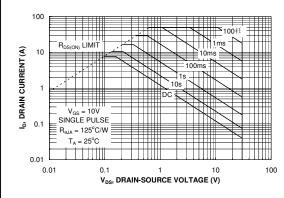


Figure 7. Gate Charge Characteristics.





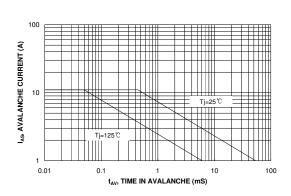
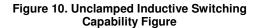


Figure 9. Maximum Safe Operating Area.



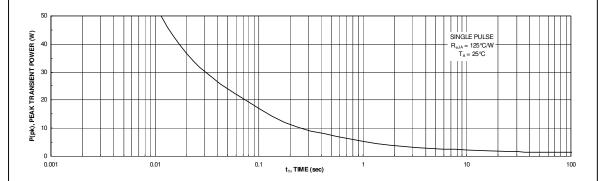


Figure 11. Single Pulse Maximum Power Dissipation.

# **Typical Characteristic**

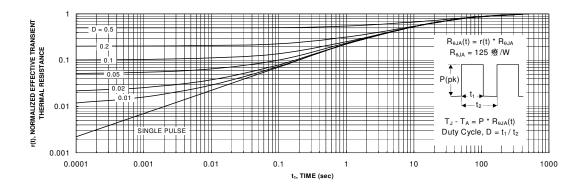


Figure 12. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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